

650V GaN FET TO-220 Series

Description

The TPH3208PS 650V, $110m\Omega$ Gallium Nitride (GaN) FET is a normally-off device. It combines state-of-the-art high voltage GaN HEMT and low voltage silicon MOSFET technologies—offering superior reliability and performance.

Transphorm GaN offers improved efficiency over silicon, through lower gate charge, lower crossover loss, and smaller reverse recovery charge.

Related Literature

- ANOOOO: Recommended External Circuitry for GaN FETs
- ANOOO3: Printed Circuit Board Layout and Probing
- ANOO10: Paralleling GaN FETs

Product Series and Ordering Information

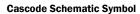
Part Number	Package	Package Configuration
TPH3208PS	3 lead T0-220	Source

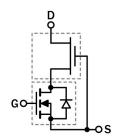












Cascode Device Structure

Features

- JEDEC qualified GaN technology
- Dynamic R_{DS(on)eff} production tested
- · Robust design, defined by
 - Intrinsic lifetime tests
 - Wide gate safety margin
 - Transient over-voltage capability
- Very low Q_{RR}
- Reduced crossover loss
- · RoHS compliant and Halogen-free packaging

Benefits

- Enables AC-DC bridgeless totem-pole PFC designs
 - Increased power density
 - Reduced system size and weight
 - Overall lower system cost
- · Achieves increased efficiency in both hard- and softswitched circuits
- Easy to drive with commonly-used gate drivers
- · GSD pin layout improves high speed design

Applications

- Datacom
- Broad industrial
- PV inverter
- Servo motor

Key Specifications		
V _{DSS} (V)	650	
V _{(TR)DSS} (V)	800	
$R_{DS(on)eff}(m\Omega)\;max^*$	130	
Q _{RR} (nC) typ	54	
Q _G (nC) typ	14	

^{*} Dynamic on-resistance; see Figures 19 and 20

Common Topology Power Recommendations			
CCM bridgeless totem-pole* 1816W max			
Hard-switched inverter**	2064W max		

Conditions: F_{SW}=45kHz; T_J=115°C; T_{HEATSINK}=90°C; insulator between device and heatsink (6 mil Sil-Pad® K-10); power de-rates at lower voltages with constant current

- VIN=230VAC; VOUT=390VDC
- V_{IN}=380V_{DC}; V_{OUT}=240V_{AC}

Absolute Maximum Ratings (T_c=25 °C unless otherwise stated.)

Symbol	Parameter		Limit Value	Unit		
V _{DSS}	Drain to source voltage (T _J = -5	55°C to 150°C)	650			
V _{(TR)DSS}	Transient drain to source volta	ge ^a	800	V		
V _{GSS}	Gate to source voltage		±18			
P _D	Maximum power dissipation @	Tc=25°C	96	W		
1	Continuous drain current @T _C =25°C b		20	A		
l _D	Continuous drain current @T _C =100°C b		Continuous drain current @T _C =100°C b		13	A
I _{DM}	Pulsed drain current (pulse width: 10µs)		80	A		
(di/dt) _{RDMC}	Reverse diode di/dt, repetitive °		1250	A/µs		
(di/dt) _{RDMT}	Reverse diode di/dt, transient	Reverse diode di/dt, transient d		A/µs		
Tc	Operating temperature	Case	-55 to +150	°C		
Tı	Operating temperature	Junction	-55 to +150	°C		
Ts	Storage temperature		-55 to +150	°C		
T _{SOLD}	Soldering peak temperature ^e		260	°C		

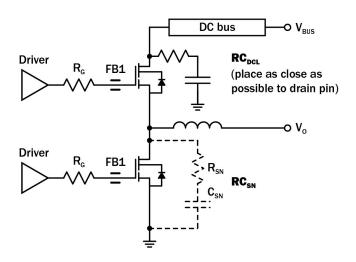
Notes:

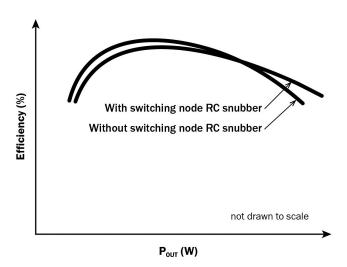
- a. In off-state, spike duty cycle D<0.01, spike duration $<1\mu$ s
- b. For increased stability at high current operation, see Circuit Implementation on page 3
- c. Continuous switching operation
- d. ≤300 pulses per second for a total duration ≤20 minutes
- e. For 10 sec., 1.6mm from the case

Thermal Resistance

Symbol	Parameter	Typical	Unit
R _{OJC}	Junction-to-case	1.3	°C/W
R _{OJA}	Junction-to-ambient	62	°C/W

Circuit Implementation





Simplified Half-bridge Schematic

Efficiency vs Output Power

Recommended gate drive: (0V, 8-10V) with $R_{G(tot)} = 25\Omega$, where $R_{G(tot)} = R_G + R_{DRIVER}$

Gate Ferrite Bead (FB1)	Required DC Link RC Snubber (RC _{DCL}) ^a	Recommended Switching Node RC Snubber (RC _{SN}) ^{b, c}
MPZ1608S331ATA00	10nF + 8Ω	22pF + 15Ω

Notes:

- a. RC_{DCL} should be placed as close as possible to the drain pin
- b. A switching node RC snubber (C, R) is recommended for high switching currents (>70% of IRDMC1 or IRDMC2; see page 5 for IRDMC1 and IRDMC2)
- c. I_{RDM} values can be increased by increasing R_{G} and C_{SN}

Electrical Parameters (T_J=25 °C unless otherwise stated)

Symbol	Parameter	Min	Тур	Max	Unit	Test Conditions
Forward Device Characteristics						
$V_{(BL)DSS}$	Drain-source voltage	650	_	_	V	V _{GS} =0V
$V_{\text{GS(th)}}$	Gate threshold voltage	1.6	2.1	2.6	V	V _{DS} =V _{GS} , I _D =0.3mA
В	Drain course on registance 3	_	110	130	0	V _{GS} =8V, I _D =13A
R _{DS(on)eff}	Drain-source on-resistance a	_	230	_	- mΩ	V _{GS} =8V, I _D =13A, T _J =150°C
	Drain to course legisare gurrent	_	3	30		V _{DS} =650V, V _{GS} =0V
I _{DSS}	Drain-to-source leakage current	_	4	_	- μΑ	V _{DS} =650V, V _{GS} =0V, T _J =150°C
	Gate-to-source forward leakage current	_	_	100	4	V _{GS} =18V
I_{GSS}	Gate-to-source reverse leakage current	_	_	-100	- nA	V _{GS} =-18V
C _{ISS}	Input capacitance	_	760	_		V _{GS} =0V, V _{DS} =400V, <i>f</i> =1MHz
Coss	Output capacitance	_	56	_	pF	
C _{RSS}	Reverse transfer capacitance	_	6	_		
C _{O(er)}	Output capacitance, energy related b	_	84	_	pF	V _{GS} =0V, V _{DS} =0V to 400V
C _{O(tr)}	Output capacitance, time related c	_	133	_	- рг	
Q _G	Total gate charge	_	10	15		V_{DS} =400V, V_{GS} =0V to 8V, I_{D} =13A
Q _{GS}	Gate-source charge	_	2.6	_	nC	
Q_{GD}	Gate-drain charge	_	2.9	_		
Qoss	Output charge	_	53.5	_	nC	V _{GS} =0V, V _{DS} =0V to 400V
t _{D(on)}	Turn-on delay	_	33	_		V _{DS} =400V, V _{GS} =0V to 10V,
t _R	Rise time	_	8	_	ns	
t _{D(off)}	Turn-off delay	_	46	_	1113	I_D =13A, R_G =22 Ω
t _F	Fall time	_	7	_]	

Notes:

a. Reflects both static and dynamic on-resistance; dynamic on-resistance test setup and waveform; see Figures 19 and 20 for conditions

b. Equivalent capacitance to give same stored energy from 0V to 400V

c. Equivalent capacitance to give same charging time from 0V to 400V

Electrical Parameters (T_J=25 °C unless otherwise stated)

Symbol	Parameter		Тур	Max	Unit	Test Conditions
Reverse Devi	Reverse Device Characteristics					
Is	Reverse current	_	_	13	А	V _{GS} =0V, T _C =100°C, ≤25% duty cycle
V_{SD}	Reverse voltage ^a	_	2.2	_	V	V _{GS} =0V, I _S =13A, T _C =25°C
VSD	Neverse voltage s	_	1.6	_	v	V _{GS} =0V, I _S =6.5A, T _C =25°C
t _{RR}	Reverse recovery time	_	22	_	ns	I _S =0A to 13A, V _{DD} =400V,
Q _{RR}	Reverse recovery charge	_	54	_	nC	di/dt=1000A/µs
(di/dt) _{RDMC}	Reverse diode di/dt, repetitive b	_	_	1250	A/µs	
I _{RDMC1}	Reverse diode switching current, repetitive (dc) ^{c, e}	_	_	13	А	Circuit implementation and parameters on page 3
I _{RDMC2}	Reverse diode switching current, repetitive (ac) c, e	_	_	17	А	Circuit implementation and parameters on page 3
(di/dt) _{RDMT}	Reverse diode di/dt, transient d	_	_	2500	A/µs	
I _{RDMT}	Reverse diode switching current, transient d,e	_	_	21	А	Circuit implementation and parameters on page 3

Notes:

- a. Includes dynamic $R_{DS(on)}$ effect
- b. Continuous switching operation
- c. Definitions: dc = dc-to-dc converter topologies; ac = inverter and PFC topologies, 50-60Hz line frequency
- d. ≤300 pulses per second for a total duration ≤20 minutes

Typical Characteristics (T_C=25 °C unless otherwise stated)

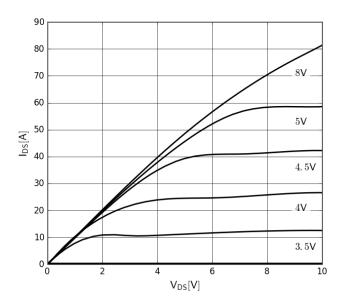


Figure 1. Typical Output Characteristics T_J=25 °C

Parameter: V_{GS}

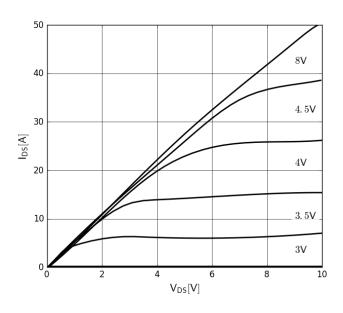


Figure 2. Typical Output Characteristics T_J=150 °C

Parameter: V_{GS}

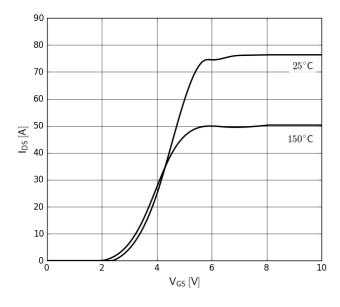


Figure 3. Typical Transfer Characteristics V_{DS} =10V, parameter: T_J

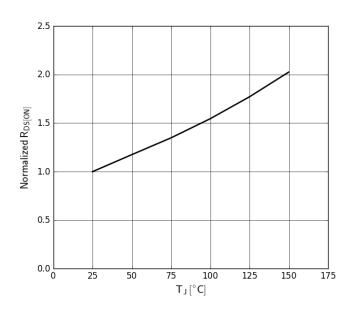
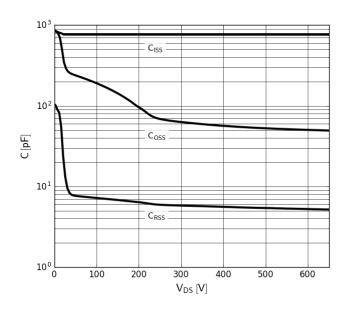


Figure 4. Normalized On-resistance $I_D=13A,\ V_{GS}=8V$

Typical Characteristics (T_C=25 °C unless otherwise stated)



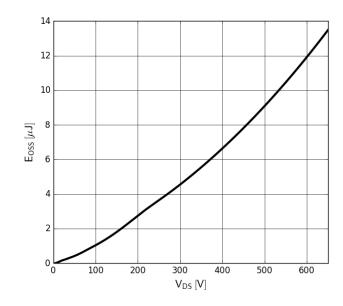
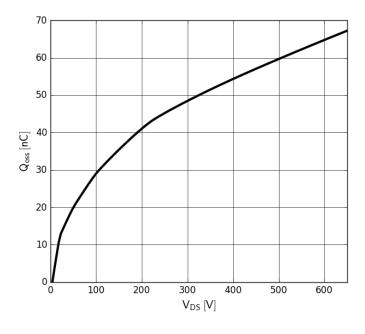


Figure 5. Typical Capacitance V_{GS} =0V, f=1MHz

Figure 6. Typical Coss Stored Energy



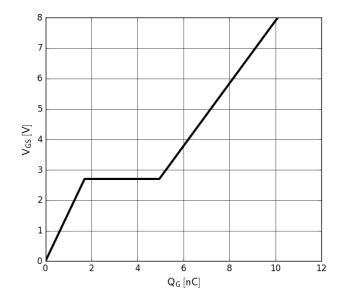


Figure 7. Typical Qoss

Figure 8. Typical Gate Charge IDS=13A, VDS=400V

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Typical Characteristics (T_C=25 °C unless otherwise stated)

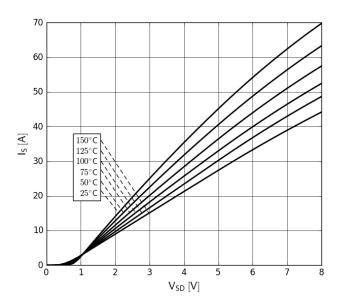


Figure 9. Forward Characteristics of Rev. Diode $I_S {=} f(V_{SD}), \ parameter {:}\ T_J$

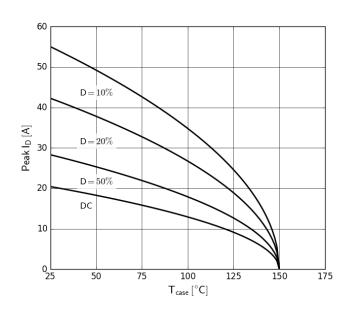


Figure 10. Current Derating
Pulse width ≤ 10µs

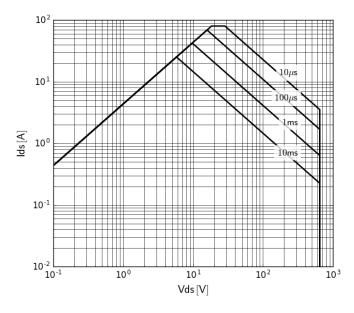


Figure 11. Safe Operating Area Tc=25°C (calculated based on thermal limit)

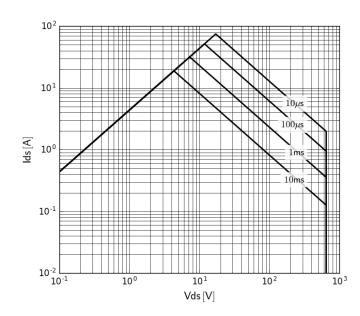
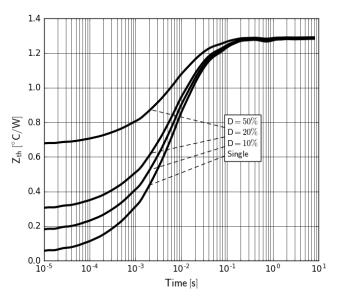


Figure 12. Safe Operating Area T_c=80 °C (calculated based on thermal limit)

Typical Characteristics (T_C =25 °C unless otherwise stated)





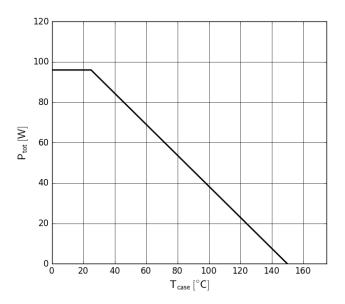


Figure 14. Power Dissipation

Test Circuits and Waveforms

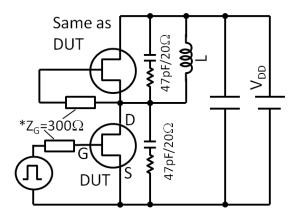


Figure 15. Switching Time Test Circuit (see circuit implementation on page 3 for methods to ensure clean switching)

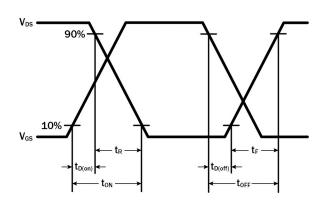


Figure 16. Switching Time Waveform

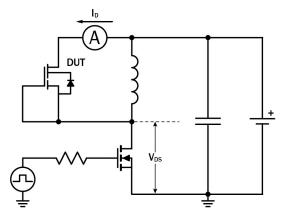


Figure 17. Diode Characteristics Test Circuit

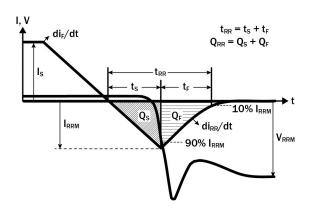


Figure 18. Diode Recovery Waveform

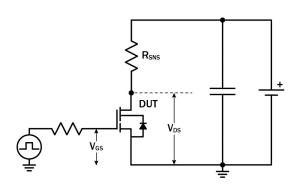


Figure 19. Dynamic R_{DS(on)eff} Test Circuit

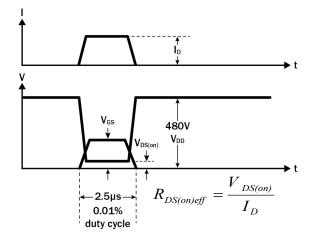


Figure 20. Dynamic R_{DS(on)eff} Waveform

Design Considerations

The fast switching of GaN devices reduces current-voltage crossover losses and enables high frequency operation while simultaneously achieving high efficiency. However, taking full advantage of the fast switching characteristics of GaN switches requires adherence to specific PCB layout guidelines and probing techniques.

Before evaluating Transphorm GaN devices, see application note <u>Printed Circuit Board Layout and Probing for GaN Power Switches</u>. The table below provides some practical rules that should be followed during the evaluation.

When Evaluating Transphorm GaN Devices:

DO	DO NOT
Minimize circuit inductance by keeping traces short, both in the drive and power loop	Twist the pins of T0-220 or T0-247 to accommodate GDS board layout
Minimize lead length of TO-220 and TO-247 package when mounting to the PCB	Use long traces in drive circuit, long lead length of the devices
Use shortest sense loop for probing; attach the probe and its ground connection directly to the test points	Use differential mode probe or probe ground clip with long wire
See AN0003: Printed Circuit Board Layout and Probing	

GaN Design Resources

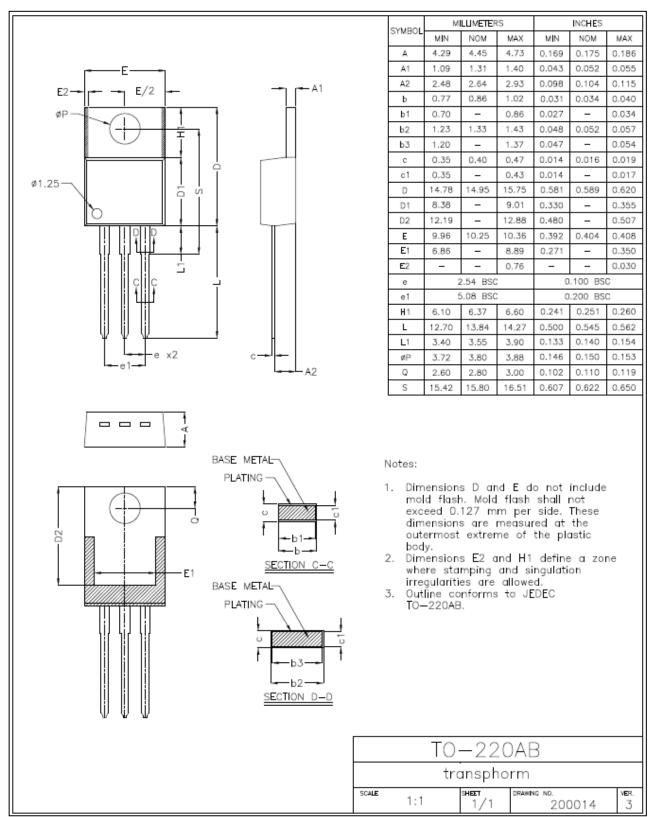
The complete technical library of GaN design tools can be found at transphormusa.com/design:

- Reference designs
- Evaluation kits
- Application notes
- · Design guides
- Simulation models
- Technical papers and presentations

Mechanical

3-lead TO-220 (PS) Package

Pin 1: Gate; Pin 2: Source; Pin 3: Drain, Tab: Source



Revision History

Version	Date	Change(s)
12	11/14/2016	Added app note AN0009
13	11/21/2016	Updated Q _G values
14	12/12/2016	Updated dynamic measurement verbiage
15	11/2/2017	Updated package drawing, Figures 11 & 12 (pg 7), effective on-resistance symbol to R _{DS(on)eff} to adhere to new JEDEC standards; Added app note AN0010, PD package option, common topology max power recommendations (pg 1), switching current values (pg 2), Circuit Implementation (pg 3), Qoss value (pg 4), Figures 7 & 8 (pg 6)
16	3/27/2018	Removed TPH3207PD